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Application/Control No.	Applicant(s)/Patent under Reexamination
09/498,856	OHNISHI ET AL.
Examiner	Art Unit
Michael J. Zanelli	3661

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	PUB Interf. arch	7/25/2006	MJZ

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